

United States Patent and Trademark Office

UNITED STATES DEPARTMENT OF COMMERCE United States Patent and Trademark Office Address: COMMISSIONER FOR PATENTS P.O. Box 1450 Alexandria, Virginia 22313-1450 www.uspto.gov

APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/706,608	11/12/2003	Jorn Maeritz	10808/111	5868
48581 75	90 07/13/2005		EXAMINER	
BRINKS HOFER GILSON & LIONE INFINEON			WALLING, MEAGAN S	
PO BOX 10395			ART UNIT	PAPER NUMBER
CHICAGO, IL 60610			2863	
			DATE MAIL ED. 07/12/2006	-

DATE MAILED: 07/13/2003

Please find below and/or attached an Office communication concerning this application or proceeding.

		AL
	Application No.	Applicant(s)
Office Action Summany	10/706,608	MAERITZ, JORN
Office Action Summary	Examiner	Art Unit
The MAN INO DATE of this communication	Meagan S. Walling	2863
The MAILING DATE of this communication a Period for Reply	appears on the cover sheet wit	n tne correspondence address
A SHORTENED STATUTORY PERIOD FOR REF THE MAILING DATE OF THIS COMMUNICATION - Extensions of time may be available under the provisions of 37 CFR after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a r - If NO period for reply is specified above, the maximum statutory perions - Failure to reply within the set or extended period for reply will, by stated any reply received by the Office later than three months after the material patent term adjustment. See 37 CFR 1.704(b).	N. 1.136(a). In no event, however, may a re reply within the statutory minimum of thirty od will apply and will expire SIX (6) MONT tute, cause the application to become ABA	ply be timely filed (30) days will be considered timely. THS from the mailing date of this communication. ANDONED (35 U.S.C. § 133).
Status		
1)⊠ Responsive to communication(s) filed on 29 2a)□ This action is FINAL. 2b)⊠ Ti 3)□ Since this application is in condition for allow closed in accordance with the practice under	his action is non-final. vance except for formal matte	•
Disposition of Claims		
4) ⊠ Claim(s) <u>1-16</u> is/are pending in the application 4a) Of the above claim(s) is/are withd 5) □ Claim(s) is/are allowed. 6) ⊠ Claim(s) <u>1-12</u> is/are rejected. 7) ⊠ Claim(s) <u>13-16</u> is/are objected to. 8) □ Claim(s) are subject to restriction and	rawn from consideration.	
Application Papers		
9) ☐ The specification is objected to by the Exami 10) ☑ The drawing(s) filed on 28 June 2004 is/are: Applicant may not request that any objection to the Replacement drawing sheet(s) including the correction. The oath or declaration is objected to by the	a)⊠ accepted or b)⊡ object ne drawing(s) be held in abeyand ection is required if the drawing(s	ce. See 37 CFR 1.85(a). s) is objected to. See 37 CFR 1.121(d).
Priority under 35 U.S.C. § 119		
12) ⊠ Acknowledgment is made of a claim for foreign a) □ All b) □ Some * c) ⊠ None of: 1. ☑ Certified copies of the priority docume 2. □ Certified copies of the priority docume 3. □ Copies of the certified copies of the priority application from the International Bure * See the attached detailed Office action for a life	ents have been received. ents have been received in Apriority documents have been received in Apriority documents have been reau (PCT Rule 17.2(a)).	oplication No received in this National Stage
Attachment(s) 1) Notice of References Cited (PTO-892)	4) ☐ Interview Su	ımmary (PTO-413)
 Notice of Draftsperson's Patent Drawing Review (PTO-948) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/C Paper No(s)/Mail Date 	Paper No(s)	/Mail Date ormal Patent Application (PTO-152)

Art Unit: 2863

DETAILED ACTION

Claim Rejections - 35 USC § 102

The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

(e) the invention was described in (1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent or (2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section 351(a) shall have the effects for purposes of this subsection of an application filed in the United States only if the international application designated the United States and was published under Article 21(2) of such treaty in the English language.

Claims 1-12 are rejected under 35 U.S.C. 102(e) as being anticipated by Whitefield et al. (US 6,512,985).

Regarding claim 1, Whitefield et al. teaches performing an analysis using values of at least one process parameter of a manufacturing process of a plurality of physical objects (column 1, lines 27-30); determining that at least one physical object of the plurality of physical objects does not satisfy a prescribed selection criterion (column 1, lines 45-49); marking the at least one physical object in such a way that the at least one marked physical object must be sent for a special measurement (column 1, lines 62-64); and removing the at least one marked physical object from the manufacturing process (column 1, lines 64-66).

Regarding claim 2, Whitefield et al. teaches that the physical object is a wafer (column 1, line 21).

Regarding claim 3, Whitefield et al. teaches that the analysis is a statistical analysis (column 1, lines 39-40).

Application/Control Number: 10/706,608

Art Unit: 2863

Regarding claim 4, Whitefield et al. teaches that the values of the at least one process parameter are measured when the plurality of physical objects is being manufactured (column 1, lines 11-13).

Regarding claim 5, Whitefield et al. teaches sending the at least one marked physical object for a special measurement (column 1, lines 64-66).

Regarding claim 6, Whitefield et al. teaches that the special measurement is a measurement for checking the quality of the at least one marked physical object (column 1, lines 64-66).

Regarding claim 7, Whitefield et al. teaches continuing the manufacturing process for any of the plurality of physical objects not marked as failing the prescribed selection criterion (see Ref. 22).

Regarding claim 8, Whitefield et al. teaches that the selection criterion is a quality characteristic of the manufacturing process (column 1, lines 16-20).

Regarding claim 9, Whitefield et al. teaches that the selection criterion is not satisfied if a value of the at least one process parameter goes above or below a prescribed limit value (column 1, lines 50-55).

Regarding claim 10, Whitefield et al. teaches performing an analysis using values of at least one process parameter of the manufacturing process of the plurality of physical objects (column 1, lines 27-30); marking at least one physical object when, as a result of the analysis, the at least one physical object does not satisfy a prescribed selection criterion (column 1, lines 62-64); removing the at least one marked physical object form the manufacturing process (column

1, lines 64-66); and sending the at least one marked physical object for special treatments (column 1, lines 64-66).

Regarding claim 11, Whitefield et al. teaches performing analysis using values of at least one process parameter of the manufacturing process of the plurality of physical objects (column 1. lines 27-30); marking at least one physical object when, as a result of the analysis, the at least one physical object does not satisfy a prescribed selection criterion (column 1, lines 62-64); removing the at least one marked physical object from the manufacturing process (column 1, lines 64-66); and sending the at least one marked physical object for special treatments (column 1, lines 64-66).

Regarding claim 12. Whitefield et al. teaches performing analysis using values of at least one process parameter of the manufacturing process of the plurality of physical objects (column 1, lines 27-30); marking at least one physical object when, as a result of the analysis, the at least one physical object does not satisfy a prescribed selection criterion (column 1, lines 62-64); removing the at least one marked physical object from the manufacturing process (column 1, lines 64-66); and sending the at least one marked physical object for special treatments (column 1, lines 64-66).

Allowable Subject Matter

Claims 13-16 are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.

The following is a statement of reasons for the indication of allowable subject matter:

Art Unit: 2863

The primary reason for the indication of allowability of claims 13-16 is the inclusion of the limitation of preventing values associated with the at least one marked physical object from affecting an average product quality of the plurality of physical objects. It is this limitation in the claimed combination that has not been found, taught, or suggested by the prior art that makes these claims allowable.

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Meagan S. Walling whose telephone number is (571) 272-2283. The examiner can normally be reached on Monday through Friday 8:30 AM to 5 PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, John Barlow can be reached on (571) 272-2269. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

msw

Supervisory Patent Examiner Technology Center 2800